

Data sheet acquired from Harris Semiconductor SCHS058C – Revised October 2003

CD4076B Types

CMOS 4-Bit D-Type Registers

High-Voltage Types (20-Volt Rating)

■ CD4076B types are four-bit registers consisting of D-type flip-flops that feature three-state outputs. Data Disable inputs are provided to control the entry of data into the flip-flops. When both Data Disable inputs are low, data at the D inputs are loaded into their respective flip-flops on the next positive transition of the clock input. Output Disable inputs are also provided. When the Output Disable inputs are both low, the normal logic states of the four outputs are available to the load. The outputs are disabled independently of the clock by a high logic level at either Output Disable input, and present a high impedance.

The CD4076B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

Features:

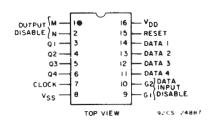
- Three-state outputs
- Input disabled without gating the clock
- Gated output control lines for enabling or disabling the outputs
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 μA at 18 V over full package temperature range; 100 nA at 18 V and 25°C
- Noise margin over full package temperature range:

1 V at V_{DD} = 5 V

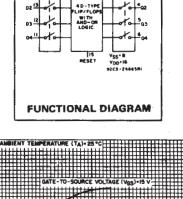
2 V at V_{DD} = 10 V

2.5 V at V_{DD} = 15 V

- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"



TERMINAL ASSIGNMENT



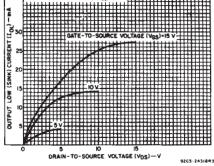


Fig.1 — Typical output low (sink) current characteristics.

RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD}	L1N	LIMITS			
	(V)	Min.	Max.			
Supply Voltage Range (For TA=Full Package Temperature Range)		3	18	v		
	5	200				
Data Setup Time, ts	10	80	-	ns		
44	15	60				
	5	200	-			
Clock Pulse Width, tw	10	100	-	ns		
* **	15	80	-			
	5		3			
Clock Input Frequency, fc1	10	dc	6	MHz		
, , , , ,	15		8			
12	5	-	15			
Clock Input Rise or Fall Time, trCL,tfCL	10	_	5	μs		
	15] –	5			
	5	120	-			
Reset Pulse Width, tw	10	50		ns		
AAA	15	40	·			
	5	180	_			
Data Input Disable Setup Time, t _S	10	100	-	ns		
	15	70	_			

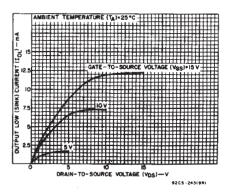


Fig.2 — Minimum output low (sink) current characteristics.

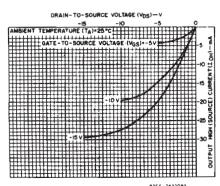


Fig.3 — Typical output high (source) current characteristics.

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CD4076B Types

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (VDD)	•
Voltages referenced to VSS Terminal)	0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	0.5V to V _{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT	
POWER DISSIPATION PER PACKAGE (PD):	
For T _A = -55°C to +100°C	500mW
For T _A = +100°C to +125°C	
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Typ	es)100mW
OPERATING-TEMPERATURE RANGE (TA)	55°C to +125°C
STORAGE TEMPERATURE RANGE (Tstg)	65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):	
At distance 1/16 \pm 1/32 inch (1.59 \pm 0.79mm) from case for 10s max .	+265°C

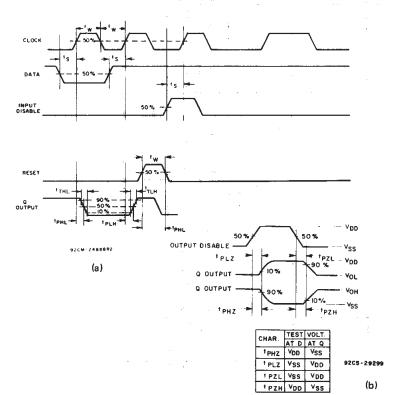


Fig.5 — Functional waveforms for CD4076B.

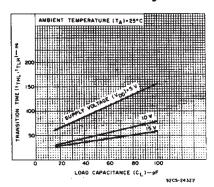


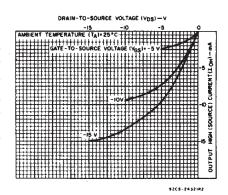
Fig.7 - Typical transition time vs. load capacitance.

Truth Table

Reset	Clock		Input sable G2	ng. Data D	Next State Output O	
1	X	x	X	x	0	
0	ô	l â	x	x	ū	NC
0		1	x	×	a ·	NC NC
0		X ^r	1	×	۵	NC
0		0	0	1	1	
0		0	0	0.	0	
0	1	x	х	х	Q	NC
0	~	×	x	×	o	NC

When either Output Disable M or N is high, the outputs are disabled (high impedance state), however sequential operation of the flip flops is not affected.

- 1 ≡ High Level 0 ≡ Low Level
- X = Don't Care



Minimum output high (source) current characteristics.

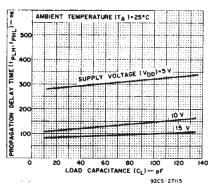


Fig.6 - Typical propagation delay time vs. load capacitance (clock to Q).

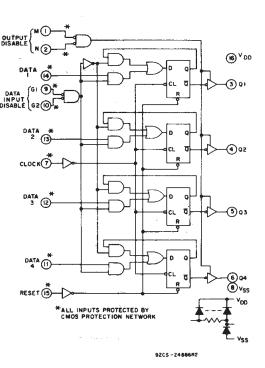


Fig.8 - CD4076B logic diagram.

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^{\circ}$ C, input $t_r, t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k Ω (Unless otherwise noted)

CHARACTERISTIC	TEST CONDI	TEST CONDITIONS				UNITS	
		V _{DD}	Min.	Тур.	Max.		
Propagation Delay Time: Clock to Q Output, tpHL, tpLH		5 10 15		300 125 90	600 250 180		
Reset, ^t PHL		5 10 15	٠.	230 100 75	460 200 150		
3-State Output 1 or 0 to High Impedance, IpHZ, IpLZ	R _L = 1 kΩ	- 5 ∉ 10 15	ŧ	1 50 75 60	300 150 120	ns	
3-State High Impedance to 1 or 0 Output, tpZH, tpZL	R _L = 1 kΩ	5 10 15		150 75 60	300 150 120	·	
Transition Time, t _{THL} t _{TLH}		5 10 15		100 50 40	200 100 80	ns	
Maximum Clock Input Frequency, f _{CL}		5 10 15	3 6 8	6 12 16		MHz	
Minimum Clock Pulse Width, t _W		5 10 15		100 50 40	200 100 80	ns	
Maximum Clock Input Rise or Fall Time, of Ircle Ifcl		5 10 15	15 5 5	. 1 1 1	1 1 1	μs :	
Minimum Reset Pulse With, t _W		5 10 15	-	60 25 20	120 50 40	ns	
Minimum Data Setup Time, t _S		5 10 15	- -	100 40 30	200 80 60	ns	
Minimum Data Input Disable Setup Time, t _S		5 .10 15	-	90 50 35	180 100 70	ns	
Input Capacitance, CIN	Any Input	- -		5	7.5	pF	

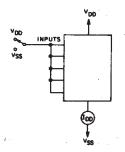


Fig.11 - Quiescent device current test circuit.

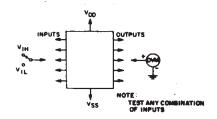


Fig. 12 - Input voltage test circuit.

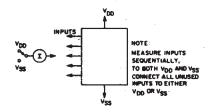


Fig. 13 - Input current test circuit.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTER-	CON	DITIO	vs	LIMITS AT INDICATED TEMPERATURES (°C)							
ISTIC	V _O	VIN	VDD	-55	-40	+65	+125	20:-	+25	24-	UNITS
_	(V) :	(V)	(V)					Min.	Тур.	Max.	ļ
Quiescent Device		0,5	5	5	5	150	150		0.04	5	1
Current,		0,10	10	10	10	300	300	-	0.04	10	μА
		0,15	15	20	20	600	600	·,	0.04	20	
		0,20	20	100	100	3000	3000		0.08	100	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
(Sink) Current 10L Min.	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6		Ī
	1.5	0,15	15	4.2	4	2.8	2.4	3 4	6.8		Ī
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	_	mA
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	1
Current, IOH Min.	9.5	0,10	10	-1.6	-1.5	1.1	-0.9	-1.3	-2.6	-	
10H mair	13.5	0,15	15	-4.2	-4	-2.8	-2.4	3.4	-6.8	-	
Output Voltage:		0,5	5 .		0	.05		_	0	, 0.05	
Low Level, VOL Max.	_	0,10	10	11	0	.05		_	0	0.05	
AOL Max	-	0,15	15		0	.05			0	0.05	
Output Voltage:	_	0,5	5	4.95				4.95	5	_	v
High-Level,	-	0,10	10		9	95		9,95	10	-	
VOH Min.		0,15	15		14	.95		14.95	15	_	
Input Low	0.5, 4.5	-	5		1,5			_		1.5	
Voltage,	1, 9	-	10			3		_	_	3	
V _{IL} Max.	1.5,13.5	_	15	4				_	_	4	
Input High	0.5, 4.5	-	5		3	.5		3.5	-		
Voltage,	1, 9	_	10			7		7	-	_	
VIH Min.	1.5,13.5	-	15	11 11					_		
Input Current IJN Max.		0,18	18	±0.1	±0.1	±1	±1	_	±10-5	±0.1	μΑ
3-State Output Leakage Current IOUT Max	0,18	0,18	18	±0.4	±0.4	±12	±12	_	±10-4	±0.4	μΑ

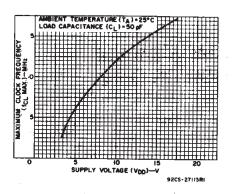


Fig.9 — Typical maximum clock input frequency vs. supply voltage.

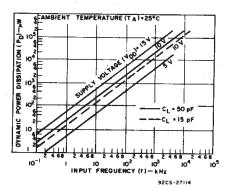
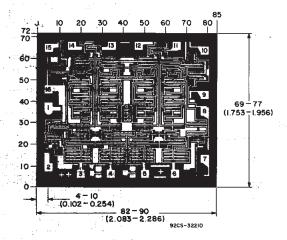


Fig. 10 — Typical dynamic power dissipation vs. frequency.



Dimensions and pad layout for CD4076BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3}) inch).





10-Jun-2014

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CD4076BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD4076BE	Samples
CD4076BEE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD4076BE	Samples
CD4076BF	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD4076BF	Samples
CD4076BF3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD4076BF3A	Samples
CD4076BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4076BM	Samples
CD4076BMG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4076BM	Samples
CD4076BMT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4076BM	Samples
CD4076BPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM076B	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

TEXAS INSTRUMENTS

10-Jun-2014

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD4076B, CD4076B-MIL:

Catalog: CD4076B

Military: CD4076B-MIL

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

• Military - QML certified for Military and Defense Applications

14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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